

5 CLAIMS:

1. A probe station for probing a device under test comprising:
  - (a) a support for holding said device under test;
  - (b) a probing device for testing said device under test while being  
10 supported by said support;
  - (c) a cable connecting said probing device to a test instrument, said  
cable including:
    - (i) a first conductor, a first dielectric, and a second conductor,  
15 where said first dielectric is between said first conductor  
and said second conductor;
    - (ii) a second dielectric, and a third conductor, where said  
second dielectric is between said second conductor and said  
third conductor;
    - (iii) further including a first layer of material between said  
20 second dielectric and said third conductor of suitable  
composition for reducing triboelectric current generation  
between said second dielectric and said third conductor to  
less than that which would occur were said second  
dielectric and said third conductor to directly adjoin each  
25 other.

5                   2.       The probe station of claim 1 further comprising a second layer of material  
between said first dielectric and said second conductor of suitable composition for  
reducing triboelectric current generation between said first dielectric and said second  
conductor to less than that which would occur were said first dielectric and said second  
conductor to directly adjoin each other.

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3.       A probe station for probing a device under test comprising:

- (a)     a support for holding said device under test;
- (b)     a probing device for testing said device under test while being  
supported by said support;

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- (c)     a cable connecting said probing device to a test instrument, said  
cable including:

- (i)     a first conductor, a first dielectric, and a second conductor,  
where said first dielectric is between said first conductor  
and said second conductor;

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- (ii)    a second dielectric, and a third conductor, where said  
second dielectric is between said second conductor and said  
third conductor;

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- (iii)   further including a first layer of material between said  
second dielectric and said second conductor of suitable  
composition for reducing triboelectric current generation  
between said second dielectric and said second conductor to

5 less than that which would occur were said second  
dielectric and said second conductor to directly adjoin each  
other.

4. The probe station of claim 3 further comprising a second layer of material  
10 between said first dielectric and said second conductor of suitable composition for  
reducing triboelectric current generation between said first dielectric and said second  
conductor to less than that which would occur were said first dielectric and said second  
conductor to directly adjoin each other.

15 5. A probe station for probing a device under test comprising:  
(a) a support for holding said device under test;  
(b) a probing device for testing said device under test while being  
supported by said support;  
(c) a cable connecting said probing device to a test instrument, said  
20 cable including:  
(i) a first conductor, a first dielectric, and a second conductor,  
where said first dielectric is between said first conductor  
and said second conductor;  
(ii) a second dielectric, and a third conductor, where said  
25 second dielectric is between said second conductor and said  
third conductor;

5 (iii) further including a first layer of material between said first  
dielectric and said first conductor of suitable composition  
for reducing triboelectric current generation between said  
first dielectric and said first conductor to less than that  
which would occur were said first dielectric and said first  
10 conductor to directly adjoin each other.

6. The probe station of claim 5 further comprising a second layer of material  
between said first dielectric and said second conductor of suitable composition for  
reducing triboelectric current generation between said first dielectric and said second  
15 conductor to less than that which would occur were said first dielectric and said second  
conductor to directly adjoin each other.

7. A cable comprising

(a) a first conductor, a first dielectric, and a second conductor, where  
20 said first dielectric is between said first conductor and said second  
conductor;

(b) a second dielectric, and a third conductor, where said second  
dielectric is between said second conductor and said third  
conductor;

25 (c) further including a first layer of material between said second  
dielectric and said third conductor of suitable composition for

5                   reducing triboelectric current generation between said second  
dielectric and said third conductor to less than that which would  
occur were said second dielectric and said third conductor to  
directly adjoin each other.

10               8.       The cable of claim 7 further comprising a second layer of material between  
said first dielectric and said second conductor of suitable composition for reducing  
triboelectric current generation between said first dielectric and said second conductor to  
less than that which would occur were said first dielectric and said second conductor to  
directly adjoin each other.

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9.       A cable comprising:

- (a)     a first conductor, a first dielectric, and a second conductor, where  
said first dielectric is between said first conductor and said second  
conductor;
- 20       (b)     a second dielectric, and a third conductor, where said second  
dielectric is between said second conductor and said third  
conductor;
- (c)     further including a first layer of material between said second  
dielectric and said second conductor of suitable composition for  
25       reducing triboelectric current generation between said second  
dielectric and said second conductor to less than that which would

5 occur were said second dielectric and said second conductor to  
directly adjoin each other.

10. The cable of claim 9 further comprising a second layer of material between  
said first dielectric and said second conductor of suitable composition for reducing  
10 triboelectric current generation between said first dielectric and said second conductor to  
less than that which would occur were said first dielectric and said second conductor to  
directly adjoin each other.

11. A cable comprising:

- 15 (a) a first conductor, a first dielectric, and a second conductor, where  
said first dielectric is between said first conductor and said second  
conductor;
- (b) a second dielectric, and a third conductor, where said second  
dielectric is between said second conductor and said third  
20 conductor;
- (c) further including a first layer of material between said first  
dielectric and said first conductor of suitable composition for  
reducing triboelectric current generation between said first  
dielectric and said first conductor to less than that which would  
25 occur were said first dielectric and said first conductor to directly  
adjoin each other.

5           12.     The probe station of claim 11 further comprising a second layer of  
material between said first dielectric and said second conductor of suitable composition  
for reducing triboelectric current generation between said first dielectric and said second  
conductor to less than that which would occur were said first dielectric and said second  
conductor to directly adjoin each other.

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